









# Test Report

Sample Name:	The integrated circuit
Sample Type:	XC7A200T-2FBG676I
Manufacturer:	XILINX
Customer:	
Customer:	

Chuangxin Online Test Center Laboratory

February 28, 2024

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# **Test Report**

#### Customer

Customer Address: N/A

Sample Name: The integrated circuit

Sample Type: XC7A200T-2FBG676I

Manufacturer: XILINX

Date Code: 22+ / 2329

Package Type: BGA-676

Sample Amount: 1600 PCS

Check Amount: 30 PCS

Arrived Date: 02/28/2024

Testing Date: 02/28/2024/11: 00 - 02/28/2024/12: 30



Tested by \_\_\_\_

Inspected by

Approved by \_\_\_\_\_

E SOL



# **Test Item**

☑ External visual inspection
☐ Pin correlation test
☐ Programming test
☐ Solderability analysis
□ Radiography(X-ray)
□ XRF test
☐ Key functional test(KFT)
□ Baking
☐ Tape and reel
☐ Top permanency test
☐ Internal visual inspection
□ SAT test
☐ Cross section

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# Methods & Equipment

#### 1.1 Test standard:

• AS6081A-2023

#### 1.2 Optical microscope:

• Equipment spec:

Optical microscope: SEZ-260 X7-X45(Due date: 7/18/2024)

## 1.3 Digital caliper:

• Equipment spec:

Digital caliper:  $(0\sim150)$  mm(Due date: 7/18/2024)

#### 1.4 Product datasheet:

• 《XILINX XC7A200T-2FBG676I》:

 $\underline{https://4donline.ihs.com/images/VipMasterIC/IC/XILI/XILI-S-A0011785145/XILI-NUMBER (Application of the content of the cont$ 

S-A0014512052-1.pdf?hkey=6D3A4C79FDBF58556ACFDE234799DDF0

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# **Analysis Summary**

## **External visual inspection:**

Applicable standard: AS6081A-2023

External visual inspection on 30 PCS samples(10 PCS of D/C 22+ and 20 PCS of D/C 2329). No secondary coating, sanding marks, crack or chips were observed on all inspected. BGA spheres were in acceptable condition. Devices package and dimension matched to manufacturer's specification.

All devices passed the external visual inspection.

#### (1) Specification dimension:

• D: 27.00 BSC mm

• E: 27.00 BSC mm

• A: 2.14-2.54 mm

## (2) Measurement dimension(D/C 22+):

• D: 26.98 mm

• E: 26.98 mm

• A: 2.32 mm

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## (3) Measurement dimension(D/C 2329):

• D: 26.99 mm

• E: 26.99 mm

• A: 2.32 mm

External visual criteria	Yes/No	Result
Mix-up	No	Pass
Top scratches	No	Pass
<b>Bottom scratches</b>	No	Pass
Chips	No	Pass
Residues	No	Pass
Indentation	No	Pass
Contamination	No	Pass
Cracks	No	Pass
Copper defect	No	Pass
Oxidization	No	Pass
Coplanarity	Yes	Pass
Sanding marks	No	Pass
Secondary coating	No	Pass
Top permanency test	N/A	N/A

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## 1. Device description:

Artix-7 FPGA DC and AC characteristics are specified in commercial, extended, industrial, expanded (-1Q), and military (-1M) temperature ranges.

## 2. Package dimension:

#### FB676, FBG676, and FBV676 (Artix-7 FPGAs) Flip-Chip Lidless BGA (1.0 mm Pitch)

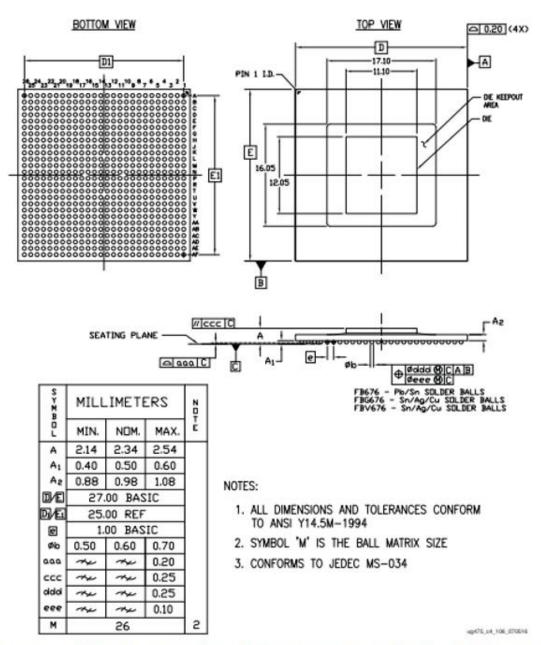


Figure 4-14: FB676, FBG676, and FBV676 Flip-Chip Lidless BGA Package Specifications for Artix-7 FPGAs

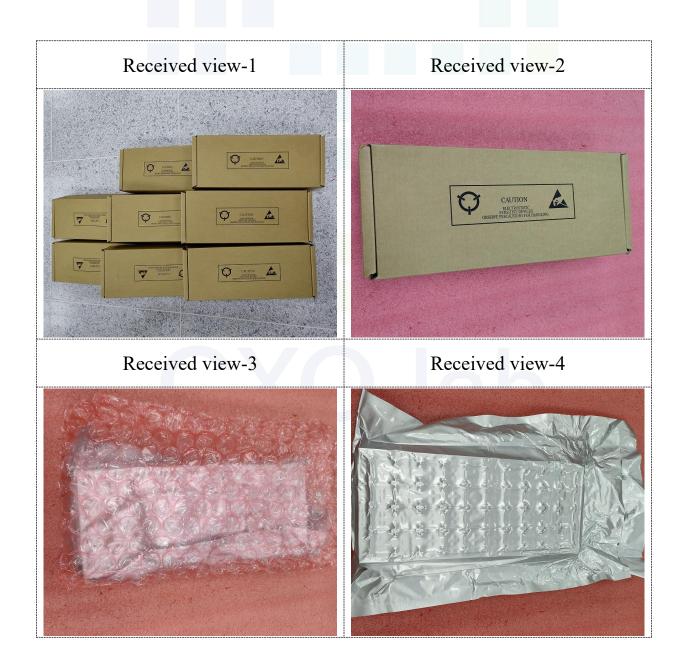
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## 3. Receiving inspection:

Gross Weight	13.0 Kg	Parts Total	1600 PCS
Number of Boxes	8	Full Label	Exist
Package Type	Tray	<b>Moisture Protection</b>	Exist
MSL	4	<b>ESD Protection</b>	Exist

Note: All devices contain 1600 PCS samples.



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#### Received view-5

#### Received view-6





Received view-7

Received view-8





Received view-9

Received view-10





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## 4. External visual inspection:

Applicable standard: AS6081A-2023

Ambient temperature: 23.3 °C Relative humidity: 55.5 % RH

External visual inspection on 30 PCS samples(10 PCS of D/C 22+ and 20 PCS of D/C 2329). No secondary coating, sanding marks, crack or chips were observed on all inspected. BGA spheres were in acceptable condition. Devices package and dimension matched to manufacturer's specification.

All devices passed the external visual inspection.

### (1) Specification dimension:

- D: 27.00 BSC mm
- E: 27.00 BSC mm
- A: 2.14-2.54 mm

#### (2) Measurement dimension(D/C 22+):

- D: 26.98 mm
- E: 26.98 mm
- A: 2.32 mm

#### (3) Measurement dimension(D/C 2329):

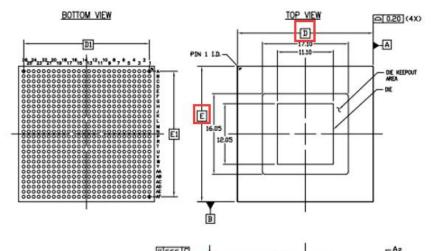
- D: 26.99 mm
- E: 26.99 mm
- A: 2.32 mm

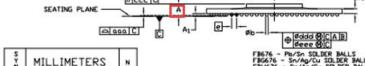
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## Package dimension

#### FB676, FBG676, and FBV676 (Artix-7 FPGAs) Flip-Chip Lidless BGA (1.0 mm Pitch)





	H	WILLINE LEKS			ZOTE
	B O L	MIN.	NOM.	MAX.	Ē
1	А	2.14	2.34	2.54	
7	A <sub>1</sub>	0.40	0.50	0.60	
	Ag	0.88	0.98	1.08	
	D/E	27.00 BASIC			
	DI/EI	25.00 REF			
	e	1.00 BASIC			
	øio	0.50	0.60	0.70	
	000	ne	me	0.20	
	ccc	ne	me	0.25	
	ddd	me	ne	0.25	
	666	ne	-Mc	0.10	
	м	26			2

#### NOTES:

- ALL DIMENSIONS AND TOLERANCES CONFORM TO ANSI Y14.5M-1994
- 2. SYMBOL 'M' IS THE BALL MATRIX SIZE
- 3. CONFORMS TO JEDEC MS-034

Figure 4-14: FB676, FBG676, and FBV676 Flip-Chip Lidless BGA Package Specifications for Artix-7 FPGAs

D/C 22+ D= 26.98 mm

$$D/C$$
 22+  $E = 26.98$  mm





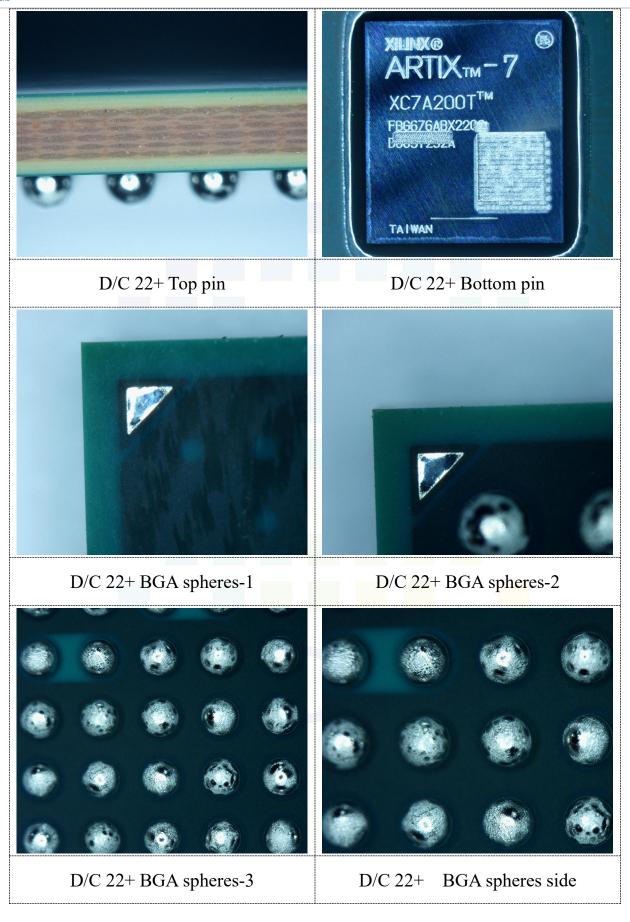
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D/C 22+ A = 2.32 mmD/C 2329 D= 26.99 mm D/C 2329 E = 26.99 mmD/C 2329 A = 2.32 mmD/C 22+ Top D/C 22+ Bottom ARTIX<sub>m</sub>-7 D/C 22+ Marking D/C 22+ Side

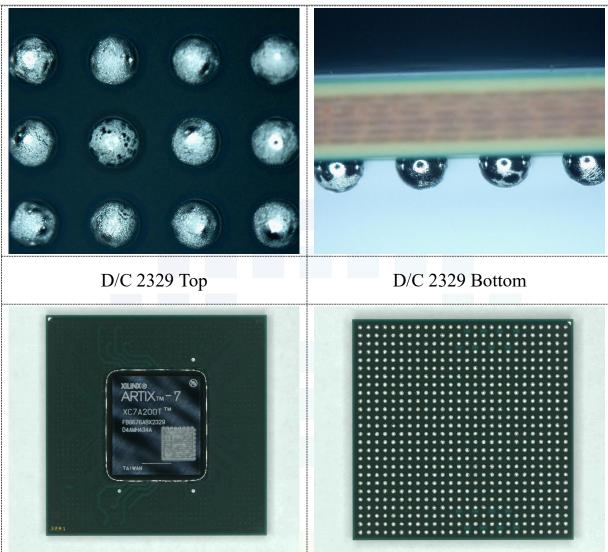
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-End of Report-





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- 2. The copy of the test report is invalid without the stamp of "company seal" and "cross-page seal".
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- 4. A modified or partial copy of the test report is invalid.
- 5. When there is disagreement with the test report, please submit the issue to us within 15 days from the date of receipt. Overdue information will not be accepted.
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- 7. The \* indicates subcontract test data.





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